

10/566843

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Sheet 1 of 2

Form PTO-1449 (REV. 1/06) US Dept. of Commerce PATENT & TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)			ATTY DOCKET NO. 125714	APPLICATION NO. New U.S. National Stage of PCT/JP2004/012114		
			APPLICANTS Susumu NODA et al.			
			FILING DATE February 2, 2006			
U.S. PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Name		
JR	1	US 2002/0191905 A1	12/19/2002	PRATHER et al.		
FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Document Number	Date	Country	With English Abstract	With English Translation
JR	2	WO 98/57207	12/17/1998	WIPO		
	3	WO 2004/068205 A1	08/12/2004	WIPO	X	
	4	WO 01/20379 A1	03/22/2001	WIPO		
	5	JP A 62-100706	05/11/1987	JAPAN	X	
	6	JP A 2001-272555	10/05/2001	JAPAN	X	X
▼	7	JP A 2001-228347	08/24/2001	JAPAN	X	X
OTHER DOCUMENTS						
Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)				
JR	8	Yoshimasa SUGIMOTO et al; 29a-YN-5; "Design and characterization of coupling-controlled directional coupler (CC-DC) Based on photonic-crystal FESTA"; March 2003; p. 1137				
	9	Yoshihiro AKAHANE et al; "Design of a channel drop filter by using a donor-type cavity with high-quality factor in a two-dimensional photonic crystal slab"; Applied Physics Letters; Volume 82, Number 9; March 3, 2003; pp. 1341-1343				
	10	Bong-Shik SONG et al; "Photonic Devices Based on In-Plane Hetero Photonic Crystals"; Science; Vol. 300; June 6, 2003; p. 1537, right column, lines 1-9, Fig. 1D				
	11	B.S. SONG et al; 29a-YN-4; "Improvement of Optical Add/Drop Filtering efficiency by using an In-Plane Hetero structure Interface"; March 2003; p. 1137				
	12	AKAHANE et al; 29a-YN-9; "Drastic Increase of Quality Factor of Defect-Cavities in 2D Photonic Crystal Slabs by Modifying Defect Structure"; March 2003; p. 1138				
▼	13	AKAHANE et al; 1p-ZM-3; "Optical Add/Drop Devices Using 2D Photonic Crystal - Design of device structures to achieve flat-top transfer function in filtering responses"; 2003; p. 944				
EXAMINER /Jerry Rahll/					DATE CONSIDERED 01/07/2007	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

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OTHER DOCUMENTS

Examiner Initials	Cite No.	(Including Author, Title, Date, Pertinent Pages, etc.)		
JR	14	Y. SUGIMOTO et al; "Design, fabrication, and characterization of coupling-strength-controlled directional coupler based on two-dimensional photonic-crystal slab waveguides"; Applied Physics Letters; October 20, 2003; Volume 83, Number 16; pp. 3236-3238		
	15	Y. AKAHANE et al; "High-Q photonic nanocavity in a two-dimensional photonic crystal"; Nature Publishing Group; October 30, 2003; Vol. 425; pp. 944-947		
	16	B.E. LITTLE et al; "Microring Resonator Channel Dropping Filters"; Journal of Lightwave Technology; Vol. 15, No. 6, June 1997; pp. 998-1005		
	17	S. FAN et al; "Channel Drop Tunneling through Localized States"; Physical Review Letters; The American Physical Society; February 2, 1998; Volume 80, Number 5; pp. 960-963		
↓	18	M.J. KHAN et al; "Mode-Coupling Analysis of Multipole Symmetric Resonant Add/Drop Filters"; IEEE Journal of Quantum Electronics; October 1999; Vol. 35; No. 10; pp. 1451-1460		

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